## Superconducting single-phase Sr<sub>1-x</sub>La<sub>x</sub>CuO<sub>2</sub> thin films with improved crystallinity grown by pulsed laser deposition

Victor Leca,<sup>a)</sup> Dave H. A. Blank, and Guus Rijnders MESA<sup>+</sup> Institute for Nanotechnology, Faculty of Science and Technology, University of Twente, 7500 AE Enschede, The Netherlands

Sara Bals and Gustaaf van Tendeloo

EMAT, University of Antwerp, Groenenborgerlaan 171, B-2020 Antwerp, Belgium

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 $\text{Sr}_{1-x}\text{La}_x\text{CuO}_{2-\delta}$  (x=0.10-0.20) thin films exhibiting an oxygen-deficient  $2\sqrt{2a_p} \times 2\sqrt{2a_p} \times c$ structure  $(a_n \text{ and } c \text{ represent the cell parameters of the perovskite subcell})$  were epitaxially grown by means of pulsed laser deposition in low-pressure oxygen ambient. (001) KTaO<sub>3</sub> and (001) SrTiO<sub>3</sub> single crystals were used as substrates, with BaTiO<sub>3</sub> as buffer layer. The Sr<sub>1-1</sub>La<sub>2</sub>CuO<sub>2- $\delta$ </sub> films were oxidized during cooling down in order to yield the infinite-layer-type structure. By applying this method, high quality single-phase  $Sr_{1-x}La_xCuO_2$  thin films could be obtained for  $0.10 \le x \le 0.175$  doping range. The films grown on BaTiO<sub>3</sub>/KTaO<sub>3</sub> show superconductivity for  $0.15 \le x \le 0.175$  with optimum doping at x=0.15, in contrast with previously reported data. © 2006 American Institute of Physics. [DOI: 10.1063/1.2339840]

The infinite-layer (IL) Sr<sub>1-x</sub>Ln<sub>x</sub>CuO<sub>2</sub> (Ln=La, Nd, Pr, Ga) compounds exhibit *n*-type superconductivity with a maximum  $T_c \sim 43$  K.<sup>1-3</sup> A solubility limit smaller than x = 0.15 was found both in bulk samples<sup>1-3</sup> and in thin films.<sup>4-6</sup> Magnetic measurements on bulk samples showed that  $T_c^{\text{onset}}$ remains constant for any doping concentration in the range  $0.05 < x \le 0.12$ , while the Meissner fraction increases with *x*, showing a maximum for  $x=0.10^{2,3}$  The decrease of the Meissner signal for x > 0.10 is associated with the impurity phases formed due to (low) solubility limit of Ln.<sup>1–3</sup> The low solubility limit is considered the reason for the shift of the optimum doping to lower values (i.e.,  $x \sim 0.10$ ) and not at the expected 0.15 electrons/CuO<sub>2</sub>.<sup>7</sup> Therefore, the upper limit for Ln doping in single-phase samples for which superconductivity can be observed has not been identified. In this perspective, it is important to find methods for yielding single-phase IL-type Sr<sub>1-x</sub>Ln<sub>x</sub>CuO<sub>2</sub> samples, mainly in the x > 0.10 region.

One of the secondary phases observed in  $Sr_{1-x}Ln_xCuO_2$ systems is the  $2\sqrt{2a_p} \times 2\sqrt{2a_p} \times c$  modulated (super)structure, where  $a_p$  and c refer to the perovskite subcell parameters.<sup>4,8</sup> Mercey *et al.*<sup>8</sup> have shown that this phase forms due to ordering of the Sr and Ln atoms, as well as of the oxygen atoms and vacancies. We have previously shown that  $\underline{Sr}_{0.85}La_{0.15}CuO_{2-\delta}$  thin films exhibiting only the  $2\sqrt{2a_p}$  $\times 2\sqrt{2a_p} \times c$  structure can be epitaxially stabilized on SrTiO<sub>3</sub> substrates by means of pulsed laser deposition (PLD).<sup>9,10</sup> According to x-ray diffraction (XRD) and high-resolution transmission electron microscopy (HRTEM) data, the modulated structure formed over a wide composition range,  $0.10 \le x$  $\leq$  0.20. This was achieved by using relatively low oxygen partial pressure (e.g., 10<sup>-2</sup> mbar O<sub>2</sub>) during growth followed by cooling down in nitrogen (1 bar). In Fig. 1 cross section HRTEM [Fig. 1(a)] and corresponding electron diffraction (ED) micrograph of the [010] plane [Fig. 1(b)] as well as plan view HRTEM [Fig. 1(c)] and corresponding ED pattern

of the [001] plane [Fig. 1(d)] of a single-phase  $Sr_{0.85}La_{0.15}CuO_{2-\delta}$  thin film exhibiting the  $2\sqrt{2a_p} \times 2\sqrt{2a_p}$  $\times c$  structure are shown. The in-plane lattice constants of these oxygen-deficient  $Sr_{1-x}La_xCuO_{2-\delta}$  films closely match the ones of the substrate.<sup>9,10</sup> The ability of this structure to match the in-plane cell parameters of the substrate may be used to obtain films with reduced strain during growth, therefore avoiding the formation of secondary phases. The questions we try to answer here are if this oxygen-deficient structure can be used as an intermediate phase in yielding single-



FIG. 1. (Color online) [(a)-(d)] Structural data of single-phase  $Sr_{0.85}La_{0.15}CuO_{2-\delta}$  thin film grown on  $SrTiO_3$  showing the  $2\sqrt{2a_p} \times 2\sqrt{2a_p}$  $\times c$  modulated structure: (a) cross section HRTEM image and (b) corresponding [010] ED pattern. In (a) the modulated structure, marked M and indicated by a white rectangle, appears as a doubling of  $a_p$ , whereas the arrow in (b) indicates a diffraction spot that is due to the modulated structure. (c) Plan view HRTEM image and (d) corresponding [001] ED pattern. The white circles in (c) indicate the size of the  $2\sqrt{2a_p} \times 2\sqrt{2a_p}$  unit cell. The bright spots in (d) correspond to the perovskite lattice parameters  $(a_n)$ , whereas the weaker spots are due to the modulated structure. [(e)-(h)] Morphological and structural data of a single-phase Sr<sub>0.85</sub>La<sub>0.15</sub>CuO<sub>2</sub> thin film grown on BaTiO<sub>3</sub>/KTaO<sub>3</sub>: (e) AFM image ( $1.5 \times 2 \ \mu m^2$ , rms ~ 0.5 nm) and (f) RHEED pattern recorded at  $10^{-3}$  mbar O<sub>2</sub> and 550 °C with [100] beam azimuth. (g) Cross section HRTEM image and (h) corresponding [010] ED pattern showing an IL-type structure. The smaller spots in (h) correspond to the (001) plane of the film.

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<sup>&</sup>lt;sup>a)</sup>Electronic mail: victor.leca@uni-tuebingen.de

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FIG. 2. (Color online) XRD  $\theta$ -2 $\theta$  patterns of Sr<sub>1-x</sub>La<sub>x</sub>CuO<sub>2- $\delta$ </sub> (x = 0.10-0.20) thin films grown on (a) BaTiO<sub>3</sub>/KTaO<sub>3</sub> and (b) BaTiO<sub>3</sub>/SrTiO<sub>3</sub>. The diffraction peaks corresponding to the substrate are marked with an asterisk; M marks the  $2\sqrt{2}a_p \times 2\sqrt{2}a_p \times c$  phase.

phase  $Sr_{1-x}La_xCuO_2$  films and, furthermore, what are the implications on the morphological, structural, and electrical properties of the resulting films. In order to obtain the superconductive phase in  $Sr_{1-x}Ln_xCuO_2$  thin films, a postdeposition reduction step that removes the apex oxygen from the Sr–O layers is generally used.<sup>4–6</sup> In this letter, however, we present a synthesis method that requires oxygenation during sample cooling in order to yield superconductivity in  $Sr_{1-x}Ln_xCuO_2$  thin films, with Ln=La.

Oxygen-deficient 75–140 nm thick  $Sr_{1-x}La_xCuO_{2-\delta}$  (x =0.10-0.20) films having a  $2\sqrt{2a_p} \times 2\sqrt{2a_p} \times c$  ordered structure were grown by means of PLD using a KrF excimer laser ( $\lambda = 248$  nm).<sup>11</sup> A substrate temperature of 550 °C and a background pressure of  $(0.5-1) \times 10^{-3}$  mbar O<sub>2</sub> were used for deposition.<sup>9,10</sup> The films were grown mainly on (001) KTaO<sub>3</sub>;<sup>6</sup> however, in order to study the role of the strain induced by the substrate on the film properties, some films were also deposited on (001) SrTiO<sub>3</sub>. BaTiO<sub>3</sub> (with thickness of  $\sim 4$  nm on KTaO<sub>3</sub> and  $\sim 20$  nm on SrTiO<sub>3</sub>, respectively) was used as buffer layer.<sup>10,12</sup> Only few unit cells of BaTiO<sub>3</sub> are deposited on KTaO<sub>3</sub> so that the buffer layer is coherent with the substrate and, therefore, fully strained. When deposited on SrTiO<sub>3</sub>, the BaTiO<sub>3</sub> layer was used to induce tensile strain in the  $Sr_{1-x}La_xCuO_2$  films with the aim of increasing their stability.<sup>13</sup> In case of KTaO<sub>3</sub>, the buffer layer helped to improve the surface morphology of the substrate.<sup>10</sup> After growth the  $Sr_{1-r}La_rCuO_{2-\delta}$  films were oxidized during cooling down to  $\sim 430 \,^{\circ}\text{C}$  (with a rate of 7.5 °C/min) inside the deposition chamber while keeping the pressure used during deposition. After reaching this temperature, the samples were placed in the loadlock for faster cooling to room temperature. A longer oxygen diffusion time resulted in lack of superconductivity in the (optimally doped) films most probably due to inclusion of interstitial oxygen. The cation composition of the films has been measured by means of x-ray fluorescence (XRF). These measurements confirmed the stoichiometric deposition except for a small Sr deficiency (up to 7.5%) in some  $Sr_{1-x}La_xCuO_2$  films grown on BaTiO<sub>3</sub>/SrTiO<sub>3</sub>.

In Fig. 1 typical atomic force microscopy (AFM) image [Fig. 1(e)] and high-pressure reflection high-energy electron diffraction (RHEED) pattern [Fig. 1(f)for Sr<sub>0.85</sub>La<sub>0.15</sub>CuO<sub>2</sub> film grown on BaTiO<sub>3</sub>/KTaO<sub>3</sub> are shown. The streaky RHEED patterns observed during growth showed that the films have a smooth surface morphology, which was confirmed by AFM. XRD data showed that the  $Sr_{1-r}La_rCuO_2$  films grown on either  $BaTiO_3/KTaO_3$  [Fig. 2(a)] or BaTiO<sub>3</sub>/SrTiO<sub>3</sub> [Fig. 2(b)] are single phase for 0.1  $\leq x \leq 0.175$  and have a tetragonal IL-type structure. The films are *c*-axis oriented and well crystallized with narrow diffraction lines for all studied doping levels. An XRD pattern for an as-deposited x=0.15 film, with the modulated structure, is shown in Fig. 2(a) (marked 0.15 M). To obtain this structure, the film was covered in situ with a SrTiO<sub>3</sub> layer and then fast cooled down in order to quench the oxygen network. The stability of this modulated structure increases with x. The unit-cell parameters (calculated from XRD data) of the as-deposited films were determined to be  $a_p \sim 3.97 - 3.99$  Å and  $c \sim 3.53 - 3.60$  Å, on BaTiO<sub>3</sub>/KTaO<sub>3</sub>,  $a_p \sim 3.95 - 3.97$  Å and  $c \sim 3.58 - 3.62$  Å, and on BaTiO<sub>3</sub>/SrTiO<sub>3</sub>, respectively. The cell-parameter values depend on the actual oxygen and La content of the samples. After oxidation, the  $Sr_{1-x}La_xCuO_2$  films grown on  $BaTiO_3/KTaO_3$  have smaller lattice constants (both a and c) axes) compared to those for the corresponding as-deposited films, due to incorporation of oxygen in the structure. However, for the films grown on  $BaTiO_3/SrTiO_3$ , the *a* axis is expanded while the c axis shrunk after the oxidation step. In case of SrTiO<sub>3</sub>, the use of BaTiO<sub>3</sub> as buffer layer results in a tensile strain in the  $Sr_{1-x}La_xCuO_2$  films that stretches the Cu–O bonds, increasing the in-plane lattice parameter of the IL films. The evolution of the unit-cell parameters with La(x)for  $Sr_{1-x}La_xCuO_{2-\delta}$  films grown on  $BaTiO_3/KTaO_3$  is presented in Table I. The films showing superconductivity have an in-plane lattice parameter close to  $a \sim 3.98$  Å. The *c*-axis cell parameter of the films shows a minimum for x=0.15.

Small amounts of the modulated structure were observed in the  $0.175 < x \le 0.20$  Sr<sub>1-x</sub>La<sub>x</sub>CuO<sub>2</sub> films due to incomplete oxygenation during cooling, as shown by the XRD patterns in Figs. 2(a) and 2(b) for x=0.20 films. Probably the conversion of the modulated structure into the IL type is hampered for higher values of x. The concentration of the modulated structure increases with x in the  $0.175 < x \le 0.20$  range, but even for these doping levels the IL is the main phase present in the films. The increased stability of the IL structure in terms of La doping can be explained by the combined effect of (a) the selected buffer layer (in case of deposition on SrTiO<sub>3</sub>) or of the KTaO<sub>3</sub> substrate with in-plane cell parameters that fit well those of the  $Sr_{1-x}La_xCuO_2$  films<sup>6</sup> and (b) by the use of the oxygen-deficient structure as intermediate phase. This reduces the possibility of nucleation of secondary phases such as  $(Sr, La)_{14}Cu_{24}O_{41-\delta}$ .<sup>9</sup> Compositional inhomogeneity is therefore avoided, as the secondary phase in the

TABLE I. Averaged XRD cell parameters of  $Sr_{1-x}La_xCuO_{2-\delta}$  ( $0.10 \le x \le 0.20$ ) thin films grown on BaTiO<sub>3</sub>/KTaO<sub>3</sub>.  $x=0.15_M$  refers to the as-deposited x=0.15 film with  $2\sqrt{2}a_p \times 2\sqrt{2}a_p \times c$  modulated structure.

x	0.10	0.125	0.15	0.175	0.20	0.15 <sub>M</sub>
a (Å)	3.965	3.968	3.978	3.981	3.987	$2\sqrt{2} \times 3.99$ $3.59$
c (Å)	3.412	3.408	3.398	3.402	3.407	

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FIG. 3. (Color online) Temperature dependence of normalized resistance  $(R_T/R_{300 \text{ K}})$  for Sr<sub>1-x</sub>La<sub>x</sub>CuO<sub>2</sub> thin films with different La contents grown on (a) BaTiO<sub>3</sub>/KTaO<sub>3</sub> and (b) BaTiO<sub>3</sub>/SrTiO<sub>3</sub>. The thickness of the BaTiO<sub>3</sub> layer on SrTiO<sub>3</sub> was ~20 nm, with postdeposition annealing at 900 °C and  $5 \times 10^{-7}$  mbar. Annealing times were 0.5 h for x=0.10, 0.15<sup>\*</sup>, and 0.20 films and 2 h for the x=0.15<sup>#</sup> film, respectively.

 $0.175 < x \le 0.20$  films contains oxygen vacancies but no cation deficiency.

In Fig. 1 a cross section HRTEM image [Fig. 1(g)] and corresponding ED pattern along the [010] plane [Fig. 1(h)] are given for a  $Sr_{0.85}La_{0.15}CuO_2$  film grown on BaTiO<sub>3</sub>/KTaO<sub>3</sub>. The film shows a single domain perovskite-type structure. No secondary phases were detected for this optimum oxidized *x*=0.15 sample, confirming the complete conversion of the as-deposited oxygen-deficient ordered structure to the IL-type structure during cooling.

The electrical properties (four-probe dc resistance) of the Sr<sub>1-x</sub>La<sub>x</sub>CuO<sub>2</sub> films as a function of La composition are presented in Fig. 3. The  $0.1 \le x \le 0.125$  films grown on BaTiO<sub>3</sub>/KTaO<sub>3</sub> showed semiconducting behavior, while for 0.125 < x < 0.15 films a semimetal-like behavior was observed [see Fig. 3(a)]. Superconductivity was observed in a relatively narrow doping range,  $0.15 \le x \le 0.175$ , with a maximum  $T_c^0 \sim 16$  K for x=0.15 and  $T_c^0 \sim 10.5$  K for x =0.175, respectively. The relatively sharp transition to superconducting state observed in the transport measurements indicates homogeneous superconducting properties in the films. The highest  $T_c^0$  values were obtained for x=0.15, which corresponds with the expected 0.15 electrons/CuO<sub>2</sub> for optimum doping. This is in contrast with the results presented to date in literature on the Sr<sub>1-r</sub>La<sub>r</sub>CuO<sub>2</sub> system, where the highest  $T_c$  was observed for x=0.10.<sup>6</sup> The electrical properties of the films grown on BaTiO<sub>3</sub>/SrTiO<sub>3</sub> [Fig. 3(b)] indicate that they are insufficiently electron doped, probably due to incomplete relaxation of the buffer layer. As a result, the BaTiO<sub>3</sub> layer does not provide sufficient tensile strain in order to promote adequate electron doping.<sup>13</sup> Superconductivity with a reduced  $T_c^0$  value of  $\sim 10$  K was observed for some x=0.15 films grown on BaTiO<sub>3</sub>/SrTiO<sub>3</sub> [the  $0.15^{\#}$  film in Fig. 3(b)] only when the buffer layer was relaxed by annealing in vacuum (2 h at 900 °C and 5  $\times 10^{-7}$  mbar) prior to the deposition of the Sr<sub>1-x</sub>La<sub>x</sub>CuO<sub>2- $\delta$ </sub> film. Presence of local cation deficiency at the Sr(La) site, as detected by XRF analysis, is another possible reason for lack of superconductivity in these films.<sup>3</sup> It is worth noting that an onset of superconductivity at ~22 K (no zero resistance at 4.2 K) was observed for some x=0.10 and x=0.125 films containing  $(Sr, La)_{14}Cu_{24}O_{41-\delta}$  as impurity phase.

Based on the transport measurements, some observations can be made: (i) the absence of the underdoped superconducting region, (ii) a narrow La doping range for superconductivity, with onset at x=0.15 and a subsequent disappearance of superconductivity for x > 0.175 with increasing concentration of electrons, and (iii) shift of the superconducting region toward a higher La doping level as compared to previous studies. Similar behavior has been reported in other electron-doped high- $T_c$  systems, e.g.,  $Nd_{2-x}Ce_xCuO_4$ ,<sup>14</sup> but not in the  $Sr_{1-r}Ln_rCuO_2$  system. A reason for the observed shift in the electronic phase diagram may be the presence of oxygen vacancies in the Cu-O planes that may generate excess charge carriers. The data presented here also suggest that the range of La doping where superconductivity is present in  $Sr_{1-r}La_rCuO_2$  may be wider than previously reported.

In summary, single-phase  $Sr_{1-x}La_xCuO_2$  thin films with an IL-type structure were grown by PLD on KTaO<sub>3</sub> and SrTiO<sub>3</sub> substrates, both buffered with BaTiO<sub>3</sub>. The IL phase is obtained after oxidation of the as-deposited oxygendeficient  $\operatorname{Sr}_{1-x}\operatorname{La}_{x}\operatorname{CuO}_{2-\delta}$  films having a  $2\sqrt{2a_{p}} \times 2\sqrt{2a_{p}} \times c$ structure. An increased stability of the IL-Sr<sub>1-x</sub>La<sub>x</sub>CuO<sub>2</sub> phases for La doping levels up to x=0.20 as well as a modified and narrower doping range for superconductivity (i.e., for  $0.15 \le x \le 0.175$ ) were observed. The x=0.15 films showed the optimum doping with a maximum  $T_c$  of 16 K. Improvement of the cooling procedure and therefore of the oxygen network may result in better superconducting properties. The presented synthesis method enables the epitaxial growth of all IL superconducting heterostructures such as superconductor-normal metal-superconductor Josephson junctions.

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